



GP 2881

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Shing M. Lee

Attorney Docket No.: KLA1P012/P647US

Application No.: 09/695,726

Examiner: Fernandez, K.

Filed: October 23, 2000

Group: 2881

Title: FILM THICKNESS MEASUREMENT
USING ELECTRON-BEAM INDUCED
X-RAY MICROANALYSIS

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CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents, Washington, DC 20231 on October 7, 2002.

Signed:

Tara Hayden

AMENDMENT TRANSMITTAL

Commissioner for Patents
Washington, DC 20231

Sir:

Transmitted herewith is an Amendment in the above-identified application.

The fee has been calculated as shown below.

	Claims After Amendment		Highest Previously Paid For	Present Extra	Small Entity Rate Fee	Large Entity Rate Fee
Total Claims	26	MINUS	30	00	x 9 =	x 18 =
Independent Claims	02	MINUS	06	00	x 42 =	x 84 =
Multiple Dependent Claim Present and Fee Not Previously Paid					\$140.00	\$280.00
				Total	\$	\$

- Applicant(s) hereby petition for a _____ month extension(s) of time to respond to the aforementioned Office Action.
- Applicant(s) believe that no (additional) Extension of Time is required; however, if it is determined that such an extension is required, Applicant(s) hereby petition that such an extension be granted and authorize the Commissioner to charge the required fees for an Extension of Time under 37 CFR 1.136 to Deposit Account No. 500388.
- Enclosed is our Check No. _____ in the amount of \$_____ to cover the additional claim fee and/or extension of time fees.
- Please charge the required fees, or any additional fees required to facilitate filing the enclosed response, to Deposit Account No. 500388 (Order No. KLA1P012).

Respectfully submitted,
BEYER WEAVER & THOMAS, LLP

Phillip P. Lee
Reg. No. 46,866

P.O. Box 778
Berkeley, CA 94704-0778



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2002.

Signed:

Tara Hayden

AMENDMENT B

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir or Madame:

In response to the Office Action dated July 5, 2002, a response to which is due October 5, 2002 please enter the following amendments and consider the following remarks:

IN THE DRAWINGS

Please amend Figures 1, 2A and 2B as indicated in red in the enclosed substitute sheet of drawing. Each of these drawings have been designated as Prior Art. A separate letter to the Official Draftsman is enclosed.

IN THE CLAIMS:

Please CANCEL claims 3, 13, 31, and 33 without prejudice or disclaimer.

Please REWRITE claims 1, 11, 21, and 26 as follows: